

March 2015

FDD86102

N-Channel Shielded Gate PowerTrench[®] MOSFET 100 V, 36 A, 24 m Ω

Features

- Shielded Gate MOSFET Technology
- Max $r_{DS(on)}$ = 24 m Ω at V_{GS} = 10 V, I_D = 8 A
- Max $r_{DS(on)}$ = 38 m Ω at V_{GS} = 6 V, I_D = 6 A
- High performance trench technology for extremely low r_{DS(on)}
- High power and current handling capability in a widely used surface mount package
- Very low Qg and Qgd compared to competing trench technologies
- Fast switching speed
- 100% UIL tested
- RoHS Compliant

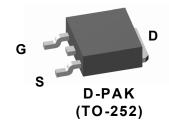


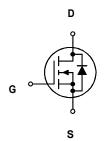
General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench® process that incorporates Shielded Gate technology. This process has been optimized for $r_{DS(on)}$, switching performance and ruggedness.

Application

■ DC - DC Conversion





MOSFET Maximum Ratings T_C = 25 °C unless otherwise noted

Symbol	Param	eter		Ratings	Units
V _{DS}	Drain to Source Voltage			100	V
V _{GS}	Gate to Source Voltage			±20	V
I _D	Drain Current -Continuous	T _C = 25 °C		36	
	-Continuous	T _A = 25 °C	(Note 1a)	8	Α
	-Pulsed		(Note 4)	75	
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	121	mJ
D	Power Dissipation	T _C = 25 °C		62	w
P_{D}	Power Dissipation	T _A = 25 °C	(Note 1a)	3.1	VV
T _J , T _{STG}	Operating and Storage Junction Tempera	ature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case		2.0	°C/W
$R_{\theta,JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	40	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD86102	FDD86102	D-PAK(TO-252)	13 "	16 mm	2500 units

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Electrical Characteristics T_J = 25 °C unless otherwise noted

Symbol	Parameter	Parameter Test Conditions		Тур	Max	Units
Off Chara	cteristics					
BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		67		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 80 V, V _{GS} = 0 V			1	μΑ
I _{GSS}	Gate to Source Leakage Current	V _{GS} = ±20 V, V _{DS} = 0 V			±100	nA

On Characteristics (Note 2)

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2	3.1	4	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C		-8.5		mV/°C
		V _{GS} = 10 V, I _D = 8 A		19	24	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 6 \text{ V}, I_D = 6 \text{ A}$		26	38	mΩ
` ′		$V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}, T_J = 125 ^{\circ}\text{C}$		33	44	
g _{FS}	Forward Transconductance	V _{DS} = 10 V, I _D = 8 A		21		S

Dynamic Characteristics

C _{iss}	Input Capacitance	. 50.7/.7/	780	1035	pF
C _{oss}	Output Capacitance	─V _{DS} = 50 V, V _{GS} = 0 V, —f = 1 MHz	180	240	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 1/11 12	15	25	pF
R_g	Gate Resistance		0.4		Ω

Switching Characteristics

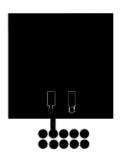
t _{d(on)}	Turn-On Delay Time			7.6	15	ns
t _r	Rise Time	V _{DD} = 50 V, I _D = 8 A,		3	10	ns
t _{d(off)}	Turn-Off Delay Time	$V_{DD} = 50 \text{ V, } I_D = 8 \text{ A,}$ $V_{GS} = 10 \text{ V, } R_{GEN} = 6$	Ω	13.4	24	ns
t _f	Fall Time			2.9	10	ns
Q_{g}	Total Gate Charge	V _{GS} = 0 V to 10 V		13.4	19	nC
Qg	Total Gate Charge	$V_{GS} = 0 \text{ V to 5 V}$	_{DD} = 50 V,	7.6	11	nC
Q_{gs}	Gate to Source Gate Charge	ID	= 8 A	4.0		nC
Q_{gd}	Gate to Drain "Miller" Charge			3.7		nC

Drain-Source Diode Characteristics

V _{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 8 \text{ A}$ (Note 2)	0.8	1.3	V
		V _{GS} = 0 V, I _S = 2.6 A (Note 2)	0.7	1.2	1 '
t _{rr}	Reverse Recovery Time	I _E = 8 A, di/dt = 100 A/μs	43	68	ns
Q _{rr}	Reverse Recovery Charge	η _F – 8 A, αι/αι – 100 Α/μs	43	68	nC

Notes:

^{1.} R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0JC} is guaranteed by design while R_{0JA} is determined by the user's board design.



a. 40 °C/W when mounted on a 1 in² pad of 2 oz copper.



 b. 96 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.
- 3. E_{AS} 121 mJ is based on starting T_J = 25 °C, L = 3 mH, I_{AS} = 9 A, V_{DD} = 100 V, V_{GS} = 10 V. 100% test at L = 0.1 mH, I_{AS} = 30 A.
- 4. Pulsed Drain current is tested at 300 µs with 2% duty cycle. For repetitive pulses, the pulse width is limited by the maximum junction temperature.

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Typical Characteristics T_J = 25 °C unless otherwise noted

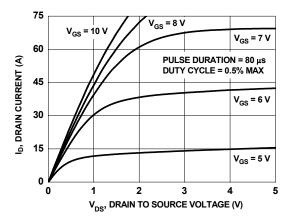


Figure 1. On-Region Characteristics

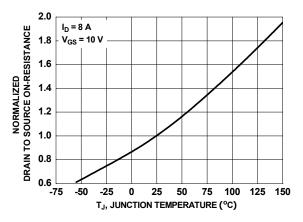


Figure 3. Normalized On-Resistance vs Junction Temperature

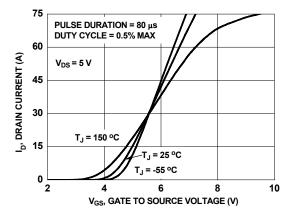


Figure 5. Transfer Characteristics

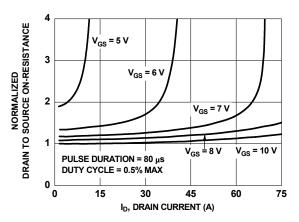


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

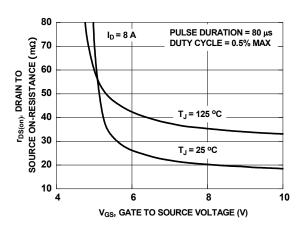


Figure 4. On-Resistance vs Gate to Source Voltage

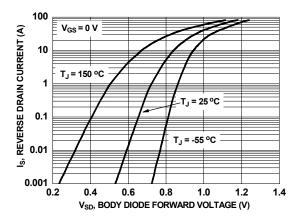


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25 °C unless otherwise noted

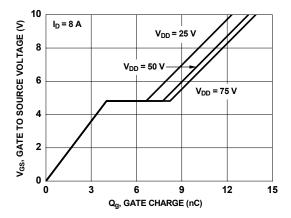
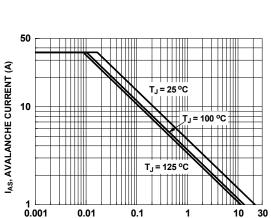


Figure 7. Gate Charge Characteristics



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Figure 9. Unclamped Inductive **Switching Capability**

t_{AV}, TIME IN AVALANCHE (ms)

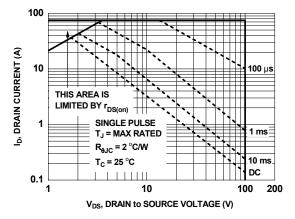


Figure 11. Forward Bias Safe **Operating Area**

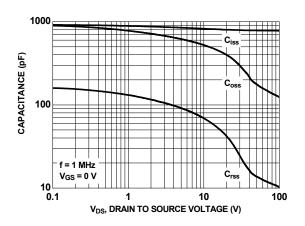


Figure 8. Capacitance vs Drain to Source Voltage

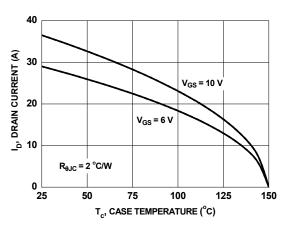


Figure 10. Maximum Continuous Drain **Current vs Case Temperature**

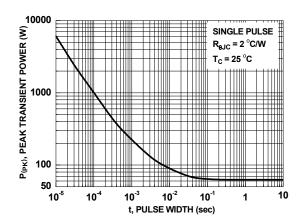


Figure 12. Single Pulse Maximum **Power Dissipation**

Typical Characteristics T_J = 25 °C unless otherwise noted

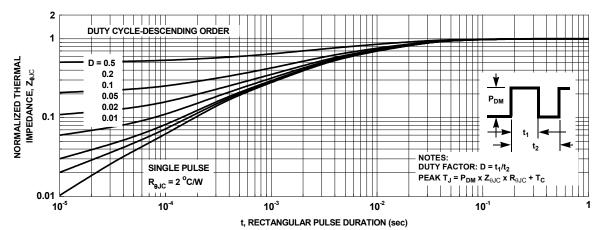
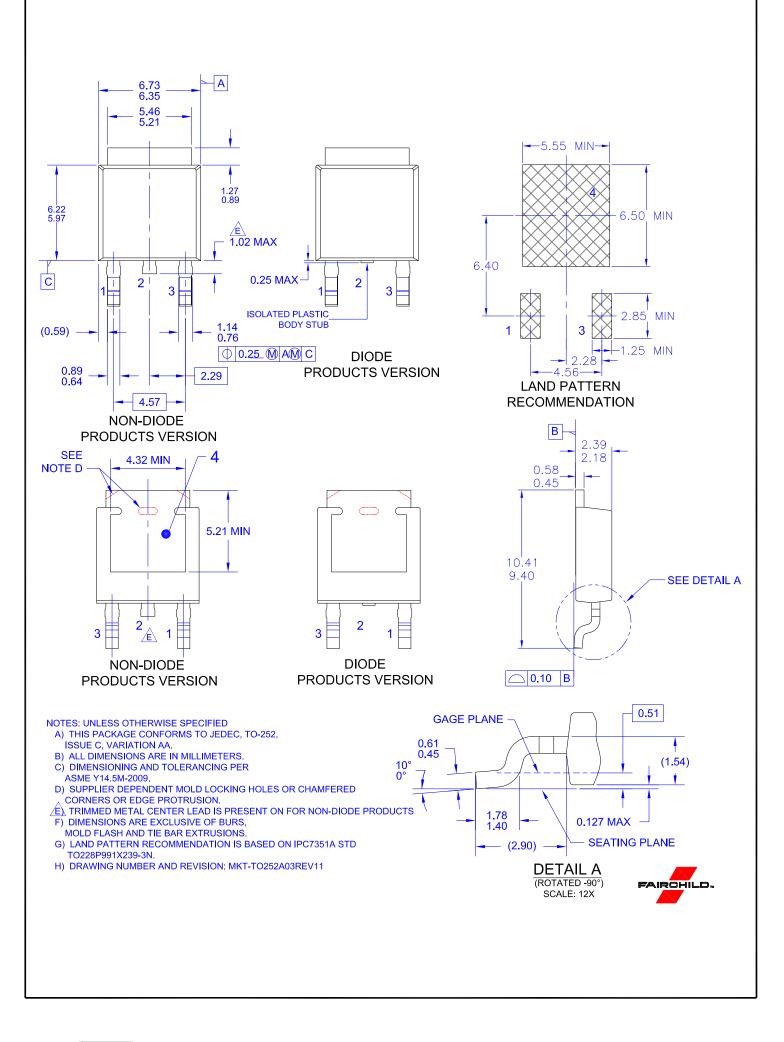


Figure 13. Junction-to-Case Transient Thermal Response Curve



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